TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC7MZ374FK

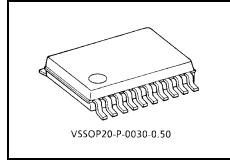
Low Voltage Octal D-Type Flip-Flop with 5 V Tolerant Inputs and Outputs

The TC7MZ374FK is a high performance CMOS octal D-type flip flop. Designed for use in 3.3 V systems, it achieves high speed operation while maintaining the CMOS low power dissipation.

The device is designed for low-voltage (3.3 V) $V_{\rm CC}$ applications, but it could be used to interface to 5 V supply environment for both inputs and outputs.

This 8 bit D-type flip-flop is controlled by a clock input (CK) and a output enable input (\overline{OE}) . When the \overline{OE} input is high, the eight outputs are in a high impedance state.

All inputs are equipped with protection circuits against static discharge.

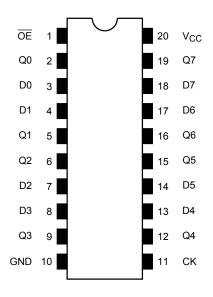


Weight: 0.03 g (typ.)

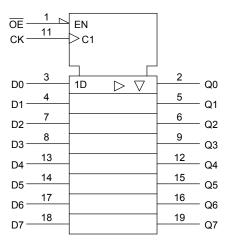
Features

- Low voltage operation: $V_{CC} = 2.0 \sim 3.6 \text{ V}$
- High speed operation: $t_{pd} = 8.5 \text{ ns (max)} (V_{CC} = 3.0 \sim 3.6 \text{ V})$
- Output current: $|I_{OH}|/I_{OL} = 24 \text{ mA (min) (V}_{CC} = 3.0 \text{ V)}$
- Latch-up performance: -500 mA
- Package: VSSOP (US20)
- Power down protection is provided on all inputs and outputs.
- Pin and function compatible with the 74 series (74AC/VHC/HC/F/ALS/LS etc.) 374 type.

Pin Assignment (top view)



IEC Logic Symbol



Truth Table

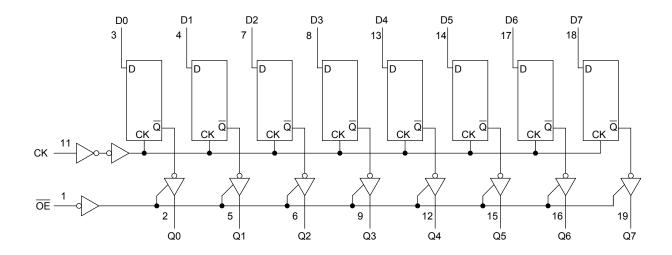
	Outputs		
ŌĒ	CK	Outputs	
Н	Х	Х	Z
L	\neg	Х	Qn
L		L	L
L		Н	Н

X: Don't care

Z: High impedance

Qn: No change

System Diagram



Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7.0	V
DC input voltage	V _{IN}	-0.5~7.0	V
DC output voltage	Va	-0.5~7.0 (Note 2)	V
DC output voltage	V _{OUT}	-0.5~V _{CC} + 0.5 (Note 3)	V
Input diode current	I _{IK}	-50	mA
Output diode current	lok	±50 (Note 4)	mA
DC output current	lout	±50	mA
Power dissipation	PD	180	mW
DC V _{CC} /ground current	I _{CC} /I _{GND}	±100	mA
Storage temperature	T _{stg}	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Output in off-state

Note 3: High or low state. I_{OUT} absolute maximum rating must be observed.

Note 4: V_{OUT} < GND, V_{OUT} > V_{CC}:

Operating Ranges (Note 1)

Characteristics	Symbol	Rating	Unit	
Supply voltage	2.0~3.6		V	
Supply voltage	V _{CC}	1.5~3.6 (Note 2)	V	
Input voltage	V _{IN}	0~5.5	V	
Output voltage	V _{OUT}	0~5.5 (Note 3)	>	
		0~V _{CC} (Note 4)		
Output current	I _{OH} /I _{OL}	±24 (Note 5)	mA	
	iOH/iOL	±12 (Note 6)	ША	
Operating temperature	T _{opr}	−40 ~ 85	°C	
Input rise and fall time	dt/dv	0~10 (Note 7)	ns/V	

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

Note 2: Data retention only

Note 3: Output in off state

Note 4: High or low state

Note 5: $V_{CC} = 3.0 \sim 3.6 \text{ V}$

Note 6: $V_{CC} = 2.7 \sim 3.0 \text{ V}$

Note 7: $V_{IN} = 0.8 \sim 2.0 \text{ V}, V_{CC} = 3.0 \text{ V}$



Electrical Characteristics

DC Characteristics ($Ta = -40 \sim 85$ °C)

Characte	eristics	Symbol	Test Condition V _{CC} (V)		V _{CC} (V)	Min	Max	Unit
l	High level	V _{IH}		_	2.7~3.6	2.0	_	V
Input voltage	Low level	V _{IL}		_	2.7~3.6		0.8	V
				$I_{OH} = -100 \mu A$	2.7~3.6	V _{CC} - 0.2	_	
	High level	V _{OH}	$V_{IN} = V_{IH}$ or V_{IL}	I _{OH} = -12 mA	2.7	2.2	_	
	-			I _{OH} = -18 mA	3.0	2.4	_	
Output voltage	Output voltage			$I_{OH} = -24 \text{ mA}$	3.0	2.2	_	V
				$I_{OL} = 100 \; \mu A$	2.7~3.6	_	0.2	
	V/a.	VIN = VIH or VIL	$I_{OL} = 12 \text{ mA}$	2.7	_	0.4		
	Low level V _{OL}	VOL	VIN = VIH OI VIL	I _{OL} = 16 mA	3.0	_	0.4	
				$I_{OL} = 24 \text{ mA}$	3.0	_	0.55	
Input leakage cu	ırrent	I _{IN}	V _{IN} = 0~5.5 V		2.7~3.6	_	±5.0	μА
2 state output of	0		$V_{IN} = V_{IH}$ or V_{IL}		2.7~3.6		±5.0	μА
3-state output off-state current I _{OZ}		IOZ	V _{OUT} = 0~5.5 V		2.1~3.0			
Power off leakag	ge current	loff	$V_{IN}/V_{OUT} = 5.5 \text{ V}$		0		10.0	μΑ
Quiescent supply current		laa	V _{IN} = V _{CC} or GND		2.7~3.6	_	10.0	
Quiescent suppi	y current	Icc	V _{IN} /V _{OUT} = 3.6~5.5 V		2.7~3.6		±10.0	μΑ
Increase in I _{CC}	per input	Δlcc	$V_{IH} = V_{CC} - 0.6 V$ 2		2.7~3.6	_	500	

AC Characteristics ($Ta = -40 \sim 85$ °C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Min	Max	Unit
Manifestore also de for account			2.7	_	_	MHz
Maximum clock frequency	f _{max}	Figure 1, Figure 2	3.3 ± 0.3	150	_	
Propagation delay time (CK O)	t _{pLH}	Figure 1 Figure 2	2.7	_	9.5	no
Propagation delay time (CK-Q)	t _{pHL}	Figure 1, Figure 2	3.3 ± 0.3	1.5	8.5	ns
Output enable time	t _{pZL}	Figure 1, Figure 3	2.7	_	9.5	ns
Output enable time	t _{pZH}	Figure 1, Figure 3	3.3 ± 0.3	1.5	8.5	
Output disable time	t _{pLZ}	Figure 1, Figure 3	2.7	_	8.5	ns
	t _{pHZ}	Figure 1, Figure 3	3.3 ± 0.3	1.5	7.5	
Minimum mula a middle (CIC)	t _w (H)	Figure 1, Figure 2	2.7	4.0	_	- ns
Minimum pulse width (CK)	t _W (L)		3.3 ± 0.3	3.3	_	
Minimum set-up time		Figure 1, Figure 2	2.7	2.5	_	ns
	t _s		3.3 ± 0.3	2.5	_	115
Minimum hold time	+.	Figure 1, Figure 2	2.7	1.5	_	ns
	t _h	Figure 1, Figure 2	3.3 ± 0.3	1.5	_	115
Outrout to outrout alcour	t _{osLH}	ALLEN	2.7			ns
Output to output skew tosHL		(Note)	3.3 ± 0.3		1.0	115

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Note: This parameter is guaranteed by design.

 $(t_{\text{OSLH}} = |t_{\text{pLHm}} - t_{\text{pLHn}}|, \, t_{\text{OSHL}} = |t_{\text{pHLm}} - t_{\text{pHLn}}|)$

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(Ta = 25°C, Input: $t_r = t_f = 2.5$ ns, $C_L = 50$ pF, $R_L = 500$ Ω)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Quiet output maximum dynamic V _{OL}	V _{OLP}	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	8.0	٧
Quiet output minimum dynamic V _{OL}	V _{OLV}	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	8.0	V

Capacitive Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	- Тур.	Unit
Input capacitance	C _{IN}	_	3.3	7	pF
Output capacitance	C _{OUT}	_	3.3	8	pF
Power dissipation capacitance	C _{PD}	$f_{IN} = 10 \text{ MHz}$	ote) 3.3	25	pF

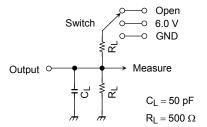
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per bit)}$



AC Test Circuit



Parameter	Switch
t _{pLH} , t _{pHL}	Open
t _{pLZ} , t _{pZL}	6.0 V
t _{pHZ} , t _{pZH}	GND
t _w , t _s , t _h , f _{max}	Open

Figure 1

AC Waveform

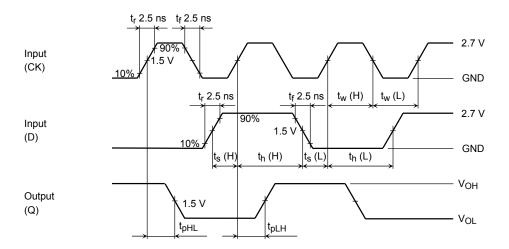


Figure 2 t_{pLH} , t_{pHL} , t_w , t_s , t_h

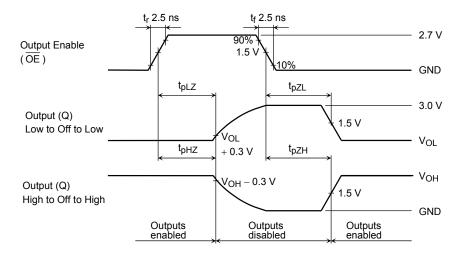
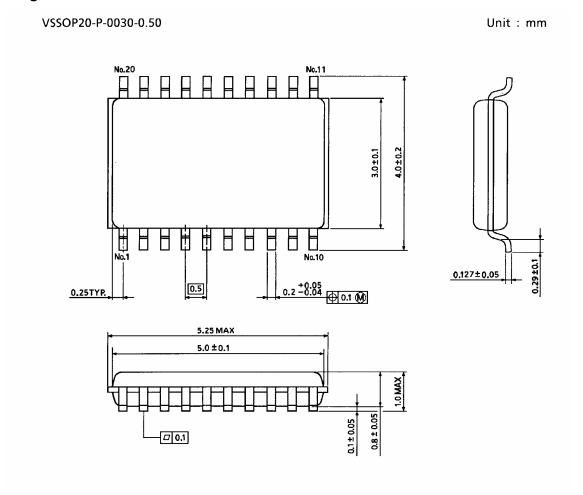


Figure 3 t_{pLZ} , t_{pHZ} , t_{pZL} , t_{pZH}

Package Dimensions



Weight: 0.03 g (typ.)

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20070701-EN GENERAL

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